Abstracts

Leakage in Coplanar Waveguides with Finite Metallization Thickness and Conductivity

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The interesting phenomenon of leakage in a practical coplanar waveguide structure with finite metallization thickness and conductivity is investigated. By applying the modified spectral-domain approach, its attenuation constants due to both leakage and conductor loss are compared and discussed. In particular, the effective dielectric constant and attenuation constant are carefully studied, together with the current distributions within the metallic signal strip and ground planes.

❑ Return to main document.